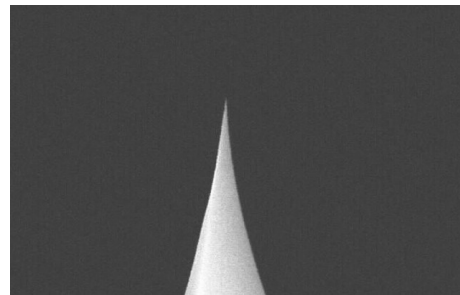


ACT-SS

ACT-SS probes are Super-Sharp silicon probes designed for Non-Contact, Tapping Mode, Intermittent Contact, and/or Close Contact applications. These probes have a high frequency that allows for faster scanning speeds. Our Super Sharp probes yield enhanced resolution images.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** >3.5
- **ROC (nm) :** 2
- **Coating:** None



Cantilever Specifications

Material	: Silicon
Shape	: Rectangular
Reflex coating	: None

Parameter	Nominal	Min	Max
k (N/m)	37	13	77
f (kHz)	300.0	200.0	400.0
Length (μm)	125.0	115.0	135.0
Width (μm)	30.0	25.0	35.0
Thickness (μm)	4.00	3.50	4.50